

REVISIONS																			
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED																
A	Changes IAW NOR 5962-R057-95.	95-01-19	K. Cottongim																
B	Made technical changes to table I for the I_{EE} , V_{TH} , V_{OUT} , t_{F1} , t_{r1} , t_{F2} , and t_{r2} tests. Redrew entire document.-sld	97-08-07	K. Cottongim																

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REV STATUS OF SHEETS	REV	B	B	B	B	B	B	B	B	B	B	B	B	B	B	B	B
	SHEET	1	2	3	4	5	6	7	8	9	10	11	12	13	14		

PMIC N/A STANDARD MICROCIRCUIT DRAWING THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE AMSC N/A	PREPARED BY Gary Zahn CHECKED BY Michael C. Jones APPROVED BY Kendall A. Cottongim DRAWING APPROVAL DATE 93-03-08 REVISION LEVEL B	DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000 MICROCIRCUIT, HYBRID, LINEAR, DUAL REDUNDANT, REMOTE TERMINAL, BUS INTERFACE UNIT <table border="1" style="width: 100%; border-collapse: collapse;"> <tr> <td style="width: 15%;">SIZE A</td> <td style="width: 35%;">CAGE CODE 67268</td> <td style="width: 50%; text-align: center;">5962-92162</td> </tr> <tr> <td colspan="3">SHEET 1 OF 14</td> </tr> </table>	SIZE A	CAGE CODE 67268	5962-92162	SHEET 1 OF 14		
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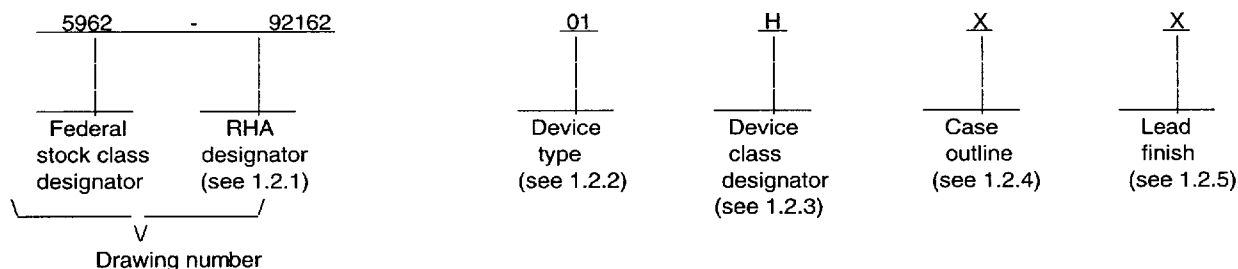
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1. SCOPE

1.1 Scope. This drawing forms a part of a one part - one part number documentation system (see 6.6 herein). This drawing describes device requirements for hybrid microcircuits to be processed in accordance with MIL-PRF-38534. Two product assurance classes, military high reliability (device class H) and space application (device class K) and a choice of case outlines and lead finishes are available and are reflected in the Part or Identifying Number (PIN). When available, a choice of radiation hardness assurance levels are reflected in the PIN.

1.2 PIN. The PIN shall be as shown in the following example:



1.2.1 Radiation hardness assurance (RHA) designator. Device classes H and K RHA marked devices shall meet the MIL-PRF-38534 specified RHA levels and shall be marked with the appropriate RHA designator. A dash (-) indicates a non-RHA device.

1.2.2 Device type(s). The device type(s) shall identify the circuit function as follows:

Device type	Generic number	Circuit function
01	BUS-65153	Small Terminal Interface Circuit (STIC), -15 V
02	BUS-65154	Small Terminal Interface Circuit (STIC), -12 V

1.2.3 Device class designator. This device class designator shall be a single letter identifying the product assurance level as follows:

Device class	Device requirements documentation
H or K	Certification and qualification to MIL-PRF-38534

1.2.4 Case outline(s). The case outline(s) shall be as designated in MIL-STD-1835 and as follows:

Outline letter	Descriptive designator	Terminals	Package style
X	See figure 1	70	Plug-in package (ceramic)
Y	See figure 1	70	Flat pack (ceramic)

1.2.5 Lead finish. The lead finish shall be as specified in MIL-PRF-38534 for classes H and K. Finish letter "X" shall not be marked on the microcircuit or its packaging. The "X" designation is for use in specifications when lead finishes A, B, and C are considered acceptable and interchangeable without preference.

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1.3 Absolute maximum ratings. 1/

V _{DD} supply voltage range	-0.5 V dc to +7.0 V dc
V _{EE} supply voltage range:	
Device type 01	-18 V dc to +0.3 V dc
Device type 02	-15 V dc to +0.3 V dc
Input voltage range	-0.5 V dc to V _{DD} + 0.5 V dc
Differential input voltage 2/	50 Vp-p
Storage temperature range	-65°C to +150°C
Power dissipation (P _D)	3/
Lead temperature (soldering, 10 seconds)	+300°C
Junction temperature (T _J)	+160°C
Thermal resistance, junction-to-case (θ _{JC})	+5.54°C/W

1.4 Recommended operating conditions.

V _{DD} supply voltage range	+4.5 V dc to +5.5 V dc
V _{EE} supply voltage range:	
Device type 01	-15.75 V dc to -14.25 V dc
Device type 02	-12.75 V dc to -11.25 V dc
Case operating temperature range (T _C)	-55°C to +125°C

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbook. Unless otherwise specified, the following specification, standards, and handbook of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

PERFORMANCE

MIL-PRF-38534 - Hybrid Microcircuits, General Specification for.

STANDARDS

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.
 MIL-STD-973 - Configuration Management.
 MIL-STD-1553 - Digital Time Division Command/Response Multiplex Data Base
 MIL-STD-1835 - Microcircuit Case Outlines.

HANDBOOK

MILITARY

MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of the specification, standards, and handbook required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

- 1/ Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.
 2/ Applies between pins TX/RX A and TX/RX A, and TX/RX B and TX/RX B.
 3/ Power dissipation shall be as follows:

Condition	Device type 01	Device type 02
Hottest die (idle)	0.680 W	0.590 W
Total hybrid (idle)	1.325 W	1.295 W
Hottest die (50% duty cycle)	1.450 W	1.360 W
Total hybrid (50% duty cycle)	2.575 W	2.220 W

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2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with MIL-PRF-38534 and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38534 and herein.

3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.4 herein and figure 1.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 2.

3.2.3 Block diagram. The block diagram shall be as specified on figure 3.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full specified operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-PRF-38534. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in QML-38534.

3.6 Manufacturer eligibility. In addition to the general requirements of MIL-PRF-38534, the manufacturer of the part described herein shall maintain the electrical test data (variables format) from the initial quality conformance inspection group A lot sample, produced on the certified line, for each device type listed herein. The data should also include a summary of all parameters manually tested, and for those which, if any, are guaranteed. This data shall be maintained under document revision level control by the manufacturer and be made available to the preparing activity (DSCC-VA) upon request.

3.7 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to supply to this drawing. The certificate of compliance submitted to DSCC-VA shall affirm that the manufacturer's product meets the requirements of MIL-PRF-38534 and the requirements herein.

3.8 Certificate of conformance. A certificate of conformance as required in MIL-PRF-38534 shall be provided with each lot of microcircuits delivered to this drawing.

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38534.

4.2 Screening. Screening shall be in accordance with MIL-PRF-38534. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DSCC-VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.

(2) T_A as specified in accordance with table I in test method 1015 of MIL-STD-883.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

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TABLE I. Electrical performance characteristics

Test	Symbol	Conditions 1/ -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
+5.0 V supply current	I _{DD}	V _{DD} = +5.5 V, idle duty cycle	1,2,3	All	10	115	mA
-15 V/-12 V supply current	I _{EE}	V _{EE} = -15.75 V, idle duty cycle	1,2,3	01	-10	-50	mA
		V _{EE} = -12.75 V, idle duty cycle	1,2,3	02	-10	-50	mA
		V _{EE} = -15.75 V, 50% duty cycle, A or B bus, less the idle duty cycle	1,2,3	01	-10	-125	mA
		V _{EE} = -12.75 V, 50% duty cycle, A or B bus, less the idle duty cycle	1,2,3	02	-10	-135	mA
Input high current	I _{IH}	CS, WRT, TESTMODE, DB00 - 15, and A00 - 13, V _{IN} = 2.7 V	1,2,3	All		±20	μA
		All other inputs, V _{IN} = 2.7 V	1,2,3	All		±5.0	μA
Input low current	I _{IL}	CS, WRT, TESTMODE, DB00 - 15, and A00 - 13, V _{IN} = 0.4 V	1,2,3	All		±20	μA
		All other inputs, V _{IN} = 0.4 V	1,2,3	All		±5.0	μA
Output high current 2/	I _{OH}		1,2,3	All	+3.4		mA
Output low current 2/	I _{OL}		1,2,3	All		-3.4	mA
Input high voltage 2/	V _{IH}		1,2,3	All	2.0		V
Input low voltage 2/	V _{IL}		1,2,3	All		0.8	V
Output high voltage	V _{OH}	I _{OH} = -3.4 mA	1,2,3	All	3.7		V
		I _{OH} = 0 mA 2/	1,2,3	All	V _{CC} - 0.4		V

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions <u>1/</u> $-55^{\circ}\text{C} \leq T_C \leq +125^{\circ}\text{C}$ unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Output low voltage	V_{OL}	$I_{OL} = -3.4 \text{ mA}$	1,2,3	All		0.5	V
		$I_{OL} = 0 \text{ mA}$ <u>2/</u>	1,2,3	All		0.4	V
Receiver differential input resistance <u>2/ 3/ 4/ 5/ 6/ 7/</u>	R_{IN}		4,5,6	All	4		k Ω
Receiver differential input capacitance <u>2/ 3/ 4/ 5/ 6/ 7/</u>	C_{IN}		4,5,6	All		10	pF
Receiver threshold voltage	V_{TH}	Transformer coupled, measured on stub	4,5,6	All	500	860	mVp-p
Receiver common mode voltage <u>2/ 8/</u>	V_{CM}		4,5,6	All		10	Vpk
Transmitter differential output voltage	V_{OUT}	Direct coupled across 35 ohm load <u>2/</u>	4,5,6	All	6.0	9.0	Vp-p
		Transformer coupled on stub, 70 ohm load	4,5,6	<u>01</u>	20	27	Vp-p
				<u>02</u>	18	27	
Transmitter differential <u>2/</u> output noise	e_n	Direct coupled across 35 ohm load	4,5,6	All		10	mVp-p
Transmitter output offset voltage <u>9/</u>	V_{OS}	Transformer coupled across 70 ohm load	4,5,6	All		± 250	mV
Functional tests	FT	Limited <u>10/</u>	7,8A,8B	All			
		Full <u>11/</u>	7,8A,8B	All			

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions ^{1/} -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Status sync fall time	t _{f1}		9,10,11	All	100	300	ns
Data sync rise time	t _{r1}		9,10,11	All	100	300	ns
Data bit fall time	t _{f2}		9,10,11	All	100	300	ns
Data bit rise time	t _{r2}		9,10,11	All	100	300	ns

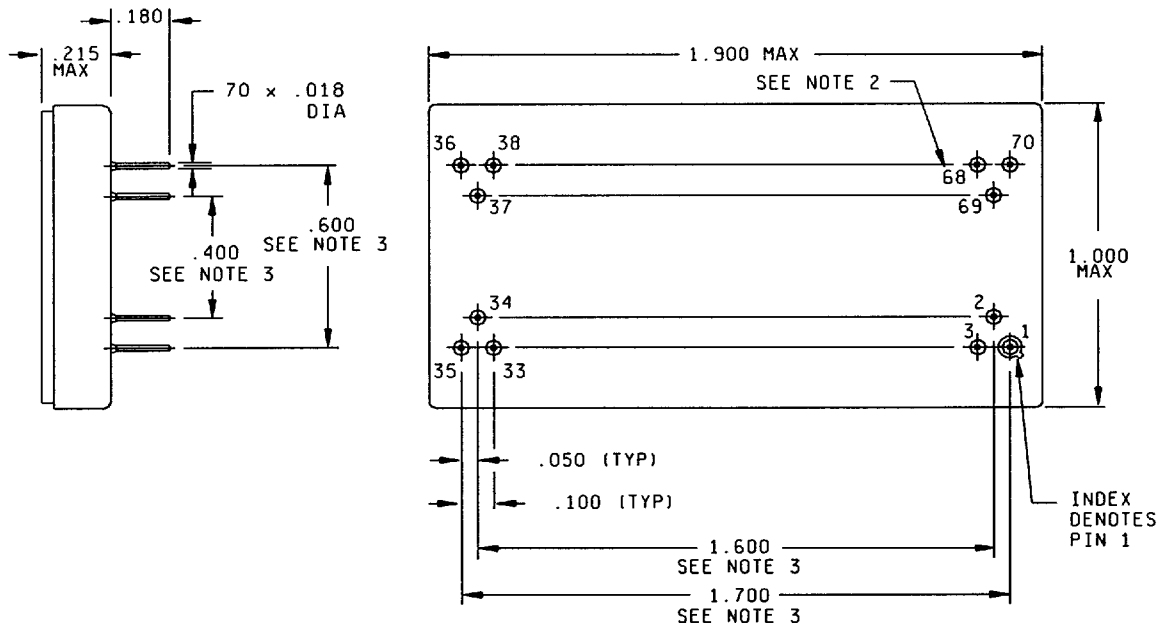
- 1/ Unless otherwise specified, +4.5 V dc ≤ V_{DD} ≤ +5.5 V dc, -15.75 V dc ≤ V_{EE} ≤ -14.25 V dc for device type 01, -12.75 V dc ≤ V_{EE} ≤ -11.25 V dc for device type 02.
- 2/ Parameter shall be tested as part of device initial characterization and after design and process changes. Parameter shall be guaranteed to the limits specified in table I for all lots not specifically tested.
- 3/ Specifications include both transmitter and receiver (tied together internally).
- 4/ Impedance measurements apply between pins TX/RX A and $\overline{\text{TX/RX A}}$, and TX/RX B and $\overline{\text{TX/RX B}}$.
- 5/ It is assumed that all power and ground inputs to the device are connected and that the device case is connected to ground for the impedance measurement.
- 6/ The specifications are applicable for both unpowered and powered conditions.
- 7/ Impedance specifications assume a 2 volt rms balanced, differential, sinusoidal input. The applicable frequency range is 75 kHz to 1 MHz.
- 8/ Assumes a common mode voltage within the frequency range of dc to 2 MHz, applied to pins of isolation transformer on stub side (either direct or transformer coupled), referenced to device ground. Transformer must have a minimum CMRR of 50 dB.
- 9/ Measured after data words 0000H, FFFFH, 5555H, AAAAH, 7FFFH, and 8000H.
- 10/ This is a quick digital test that verifies each digital input and each digital output.
- 11/ This is a comprehensive test of the MIL-STD-1553 interface, internal core logic, and subsystem interface of the device under test.

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Case outline X



Inches	mm	Inches	mm
.005	.13	.400	10.16
.018	.46	.600	15.24
.050	1.27	1.000	25.40
.100	2.54	1.600	40.64
.180	4.57	1.700	43.18
.215	5.46	1.900	48.26

NOTES:

1. Dimensions are in inches.
2. Pin numbers are for reference only and do not appear on package.
3. Lead cluster to be centralized within $\pm .010$ of outline dimensions.
4. Unless otherwise specified, tolerance: XXX = $\pm .005$
5. Metric equivalents are given for information only.

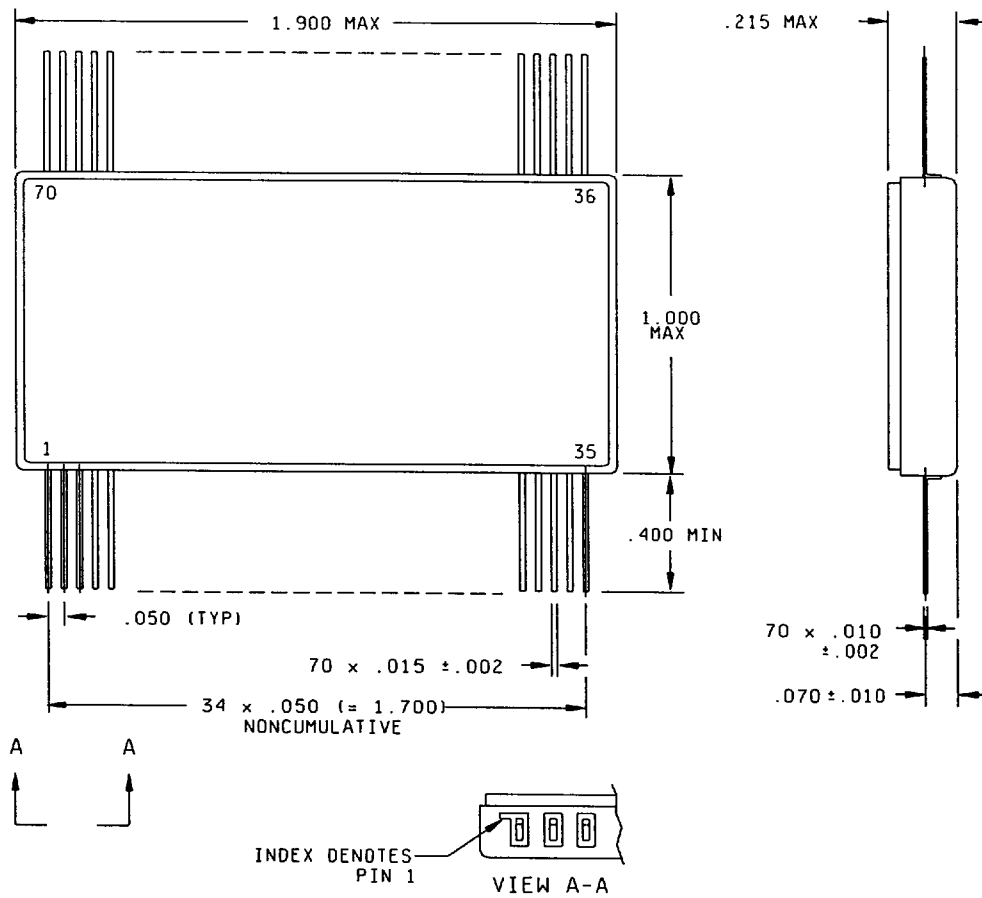
FIGURE 1. Case outline.

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Case outline Y



Inches	mm	Inches	mm
.002	.05	.070	1.78
.005	.13	.215	5.46
.010	.25	.400	10.16
.015	.38	1.000	25.40
.050	1.27	1.700	43.18
		1.900	48.26

NOTES:

1. Dimensions are in inches.
2. Pin numbers are for reference only and do not appear on package.
3. Unless otherwise specified, tolerance: XXX = ±.005
4. Metric equivalents are given for information only.

FIGURE 1. Case outline - Continued.

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Device types	01 and 02	Device types	01 and 02
Case outlines	X and Y	Case outlines	X and Y
Terminal number	Terminal symbol	Terminal number	Terminal symbol
1	DB GRT	36	-15 V/-12 V A/B 1/
2	DB ACK	37	GBR
3	CS	38	RT FAIL
4	WRT	39	NBGRT
5	RX/TX DATA B	40	RX/TX A
6	HS FAIL	41	TNCMD
7	ADDR ENA	42	ME
8	DB SEL	43	CLK SEL
9	RX/TX DATA B	44	RX/TX A
10	DB15 (MSB)	45	RESET
11	DB14	46	TEST MODE
12	DB13	47	T-A-STR
13	DB12	48	T-D-STR
14	DB11	49	TX INH
15	DB10	50	A13
16	DB09	51	CLK IN
17	DB08	52	A12
18	GND	53	A11 (MSB)
19	DB07	54	A10
20	DB06	55	A09
21	DB05	56	A08
22	DB04	57	A07
23	DB03	58	A06
24	DB02	59	A05
25	DB01	60	A04
26	DB00 (LSB)	61	A03
27	RT ADD ERR	62	A02
28	RT ADD LAT	63	A01 (LSB)
29	RT ADD PAR	64	A00
30	RT ADD00 (LSB)	65	TLLCMD
31	RT ADD01	66	SERVREQ
32	RT ADD02	67	SSFLAG
33	RT ADD03	68	BUSY
34	RT ADD04 (MSB)	69	DB REQ
35	+5.0 V A	70	+5.0 V B

1/ Pin 36 is V_{EE} (-15 V for device type 01) and (-12 V for device type 02).

FIGURE 2. Terminal connections.

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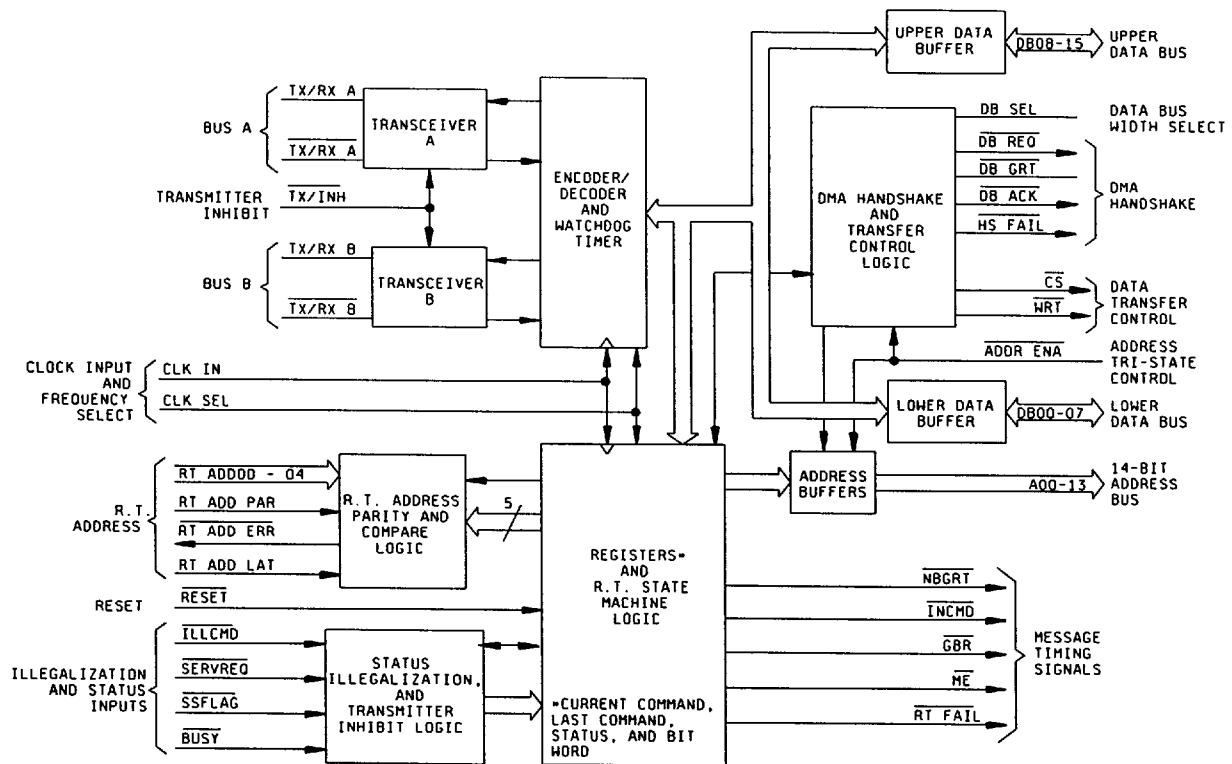


FIGURE 3. Block diagram.

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TABLE II. Electrical test requirements.

MIL-PRF-38534 test requirements	Subgroups (in accordance with MIL-PRF-38534, group A test table)
Interim electrical parameters	1,4,7,9
Final electrical test parameters	1*,2,3,4,5,6,7, 8A,8B,9,10,11
Group A test requirements	1,2,3,4,5,6,7, 8A,8B,9,10,11
Group C end-point electrical parameters	1,2,3,4,5,6,7, 8A,8B,9,10,11
MIL-STD-883, group E end-point electrical parameters for RHA devices	Subgroups ** (in accordance with method 5005, group A test table)

* PDA applies to subgroup 1.

** When applicable to this standard microcircuit drawing,
the subgroups shall be defined.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with MIL-PRF-38534 and as specified herein.

4.3.1 Group A inspection. Group A inspection shall be in accordance with MIL-PRF-38534 and tests shall be as specified in table II herein.

4.3.2 Group B inspection. Group B inspection shall be in accordance with MIL-PRF-38534.

4.3.3 Group C inspection. Group C inspection shall be in accordance with MIL-PRF-38534 and as follows:

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DSCC-VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.
 - (2) T_A as specified in accordance with table I of method 1005 of MIL-STD-883.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

4.3.4 Group D inspection. Group D inspection shall be in accordance with MIL-PRF-38534.

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4.3.5 Group E inspection. Group E inspection is required only for parts intended to be marked as radiation hardness assured (see 3.5 herein). RHA levels for device classes H and K shall be M, D, R, and H. RHA quality conformance inspection sample tests shall be performed at the RHA level specified in the acquisition document.

- a. RHA tests for device classes H and K for levels M, D, R, and H shall be performed through each level to determine at what levels the devices meet the RHA requirements. These RHA tests shall be performed for initial qualification and after design or process changes which may affect the RHA performance of the device.
- b. End-point electrical parameters shall be as specified in table II herein.
- c. Prior to total dose irradiation, each selected sample shall be assembled in its qualified package. It shall pass the specified group A electrical parameters in table I for subgroups specified in table II herein.
- d. For device classes H and K, the devices shall be subjected to radiation hardness assured tests as specified in MIL-PRF-38534 for RHA level being tested, and meet the postirradiation end-point electrical parameter limits as defined in table I at $T_A = +25^{\circ}\text{C} \pm 5$ percent, after exposure.
- e. Prior to and during total dose irradiation testing, the devices shall be biased to establish a worst case condition as specified in the radiation exposure circuit.
- f. For device classes H and K, subgroups 1 and 2 in table V, method 5005 of MIL-STD-883 shall be tested as appropriate for device construction.
- g. When specified in the purchase order or contract, a copy of the RHA delta limits shall be supplied.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38534.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-973 using DD Form 1692, Engineering Change Proposal.

6.4 Record of users. Military and industrial users shall inform Defense Supply Center Columbus when a system application requires configuration control and the applicable SMD. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0526.

6.5 Comments. Comments on this drawing should be directed to DSCC-VA, Columbus, Ohio 43216-5000 or telephone (614) 692-0512.

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6.6 One part - one part number system. The one part - one part number system described below has been developed to allow for transitions between identical generic devices covered by the three major microcircuit requirements documents (MIL-H-38534, MIL-I-38535, and 1.2.1 of MIL-STD-883) without the necessity for the generation of unique PIN's. The three military requirements documents represent different class levels, and previously when a device manufacturer upgraded military product from one class level to another, the benefits of the upgraded product were unavailable to the Original Equipment Manufacturer (OEM), that was contractually locked into the original unique PIN. By establishing a one part number system covering all four documents, the OEM can acquire to the highest class level available for a given generic device to meet system needs without modifying the original contract parts selection criteria.

<u>Military documentation format</u>	<u>Example PIN under new system</u>	<u>Manufacturing source listing</u>	<u>Document listing</u>
New MIL-H-38534 Standard Microcircuit Drawings	5962-XXXXXZZ(H or K)YY	QML-38534	MIL-BUL-103
New MIL-I-38535 Standard Microcircuit Drawings	5962-XXXXXZZ(Q or V)YY	QML-38535	MIL-BUL-103
New 1.2.1 of MIL-STD-883 Standardized Military Drawings	5962-XXXXXZZ(M)YY	MIL-BUL-103	MIL-BUL-103

6.7 Sources of supply for device classes H and K. Sources of supply for device classes H and K are listed in QML-38534. The vendors listed in QML-38534 have submitted a certificate of compliance (see 3.7 herein) to DSCC-VA and have agreed to this drawing.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-92162
		REVISION LEVEL B	SHEET 14

DESC FORM 2234
APR 97

■ 9004708 0030058 022 ■

STANDARD MICROCIRCUIT DRAWING SOURCE APPROVAL BULLETIN

DATE: 97-08-07

Approved sources of supply for SMD 5962-92162 are listed below for immediate acquisition only and shall be added to QML-38534 during the next revision. QML-38534 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This bulletin is superseded by the next dated revision of QML-38534.

Standard microcircuit drawing PIN	Vendor CAGE number	Vendor similar PIN ^{1/}
5962-9216201HXC 5962-9216201HXA	19645 19645	BUS-65153II-110 BUS-65153II-140
5962-9216201HYC 5962-9216201HYA	19645 19645	BUS-65163II-110 BUS-65163II-140
5962-9216202HXC 5962-9216202HXA	19645 19645	BUS-65154II-110 BUS-65154II-140
5962-9216202HYC 5962-9216202HYA	19645 19645	BUS-65164II-110 BUS-65164II-140

^{1/} Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE
number

19645

Vendor name
and address

ILC Data Device Corporation
105 Wilbur Place
Bohemia, NY 11716-2482

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in this information bulletin.

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